

# N-Channel 60-V (D-S) MOSFET

PRODUC	CT SUMMARY		
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)
00	0.076 at V <sub>GS</sub> = 10 V	4.5	10 nC
60	0.085 at V <sub>GS</sub> = 4.5 V	3.5	10110

#### **FEATURES**

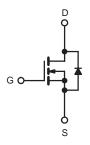
- Halogen-free
- TrenchFET<sup>®</sup> Power MOSFET



#### **APPLICATIONS**

· Load Switches for Portable Devices





N-Channel MOSFET

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V <sub>DS</sub>	60	V
Gate-Source Voltage		$V_{GS}$	± 20	
	T <sub>C</sub> = 25 °C		4.5	
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C	I_	3.2 <sup>a</sup>	
Continuous Brain Current (1) = 100 °C)	T <sub>A</sub> = 25 °C	- ID	2.7	
	T <sub>A</sub> = 70 °C		2.3	A
Pulsed Drain Current	•	I <sub>DM</sub>	20	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	3.2	
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	'S	2.1 <sup>b, c</sup>	
	T <sub>C</sub> = 25 °C		4.0	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	3.0	W
	T <sub>A</sub> = 25 °C	' D	2.5 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		1.6 <sup>b, c</sup>	
Operating Junction and Storage Temperatur	ing Junction and Storage Temperature Range T <sub>J</sub> , T <sub>stg</sub> - 55 to 150		- 55 to 150	°C
Soldering Recommendations (Peak Tempera		260		

THERMAL RESISTANCE RA	TINGS				
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>a, c, d</sup>	t ≤ 5 s	R <sub>thJA</sub>	40	50	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	15	20	] 0/11

- a. Package limited, T<sub>C</sub> = 25 °C.
  b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 95 °C/W.
- e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.



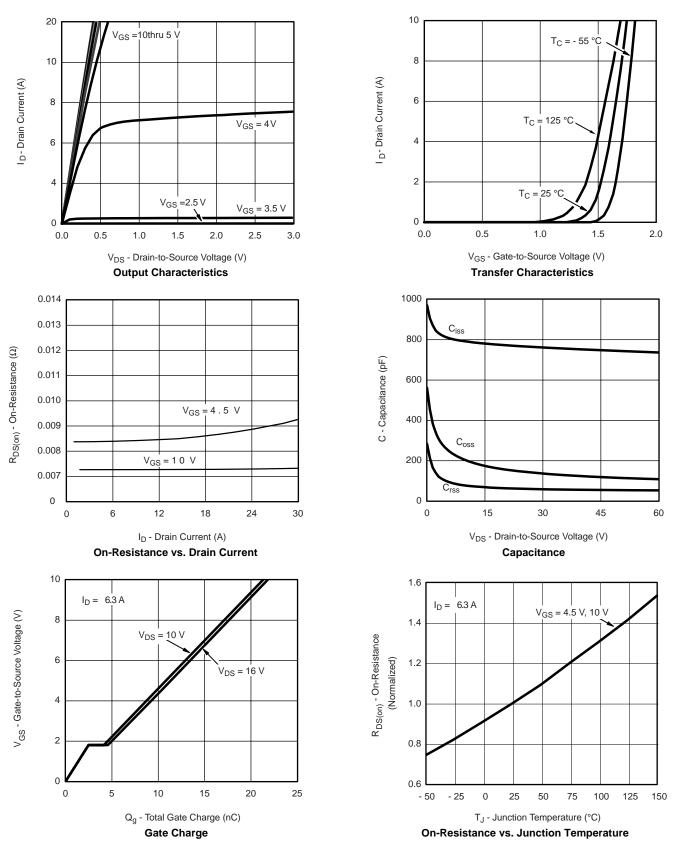
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	1				I.	•
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		25		
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 4.0		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.0		2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA
Zana Oata Wallana Busin Oamani		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	30			Α
Drain-Source On-State Resistance <sup>a</sup>		$V_{GS} = 10 \text{ V}, I_D = 4.0 \text{ A}$		0.076		Ω
	R <sub>DS(on)</sub>	$V_{GS} = 4.5  V, I_D = 3.0  A$		0.085		
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 4.0 A		45		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			810		
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 30V$ , $V_{GS} = 0$ V, $f = 1$ MHz		120		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			100		
Tatal Cata Charma		$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 4.0 \text{ A}$		22	33	nC
Total Gate Charge	Qg	Q <sub>g</sub> V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.5 / V		10	15	
Gate-Source Charge	$Q_{gs}$	$V_{DS}$ = 30 V, $V_{GS}$ = 4.5 V, $I_{D}$ = 3.0 A		2.5		
Gate-Drain Charge	$Q_{gd}$			1.7		
Gate Resistance	$R_g$	f = 1 MHz		2.4		Ω
Turn-on Delay Time	t <sub>d(on)</sub>			15	25	
Rise Time	t <sub>r</sub>	$V_{DD}$ =30V, , $R_L$ = 1.5 $\Omega$		10	15	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 4.0$ A, $V_{GEN}=4.5$ V, $R_g=1$ $\Omega$		35	55	
Fall Time	t <sub>f</sub>			12	20	
Turn-on Delay Time	t <sub>d(on)</sub>			10	15	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 30V , $R_L$ = 1.5 $\Omega$		12	20	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 4.0$ A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$		25	40	
Fall Time	t <sub>f</sub>			10	15	
<b>Drain-Source Body Diode Characteristi</b>	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			7.2	^
Pulse Diode Forward Current	I <sub>SM</sub>				30	A
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 4.0 A, V <sub>GS</sub> = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			20	40	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 4.0 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		10	20	nC
Reverse Recovery Fall Time	t <sub>a</sub>	1 τ.ο Λ, αιναι - 100 Ανμο, 1J = 25 C		10		20
Reverse Recovery Rise Time	t <sub>b</sub>	7		10		ns

#### Notes:

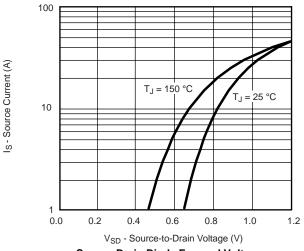
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

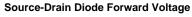
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

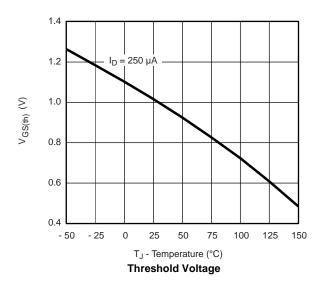






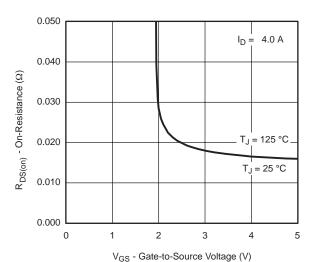




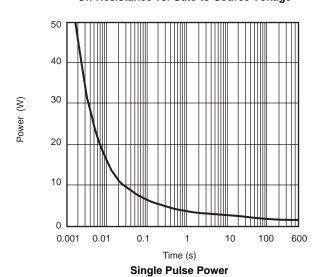


100

0.01 L 0.1



On-Resistance vs. Gate-to-Source Voltage

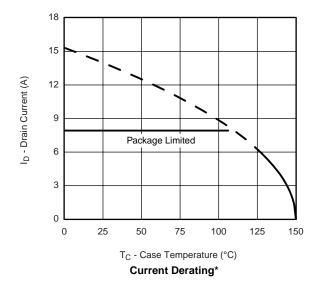


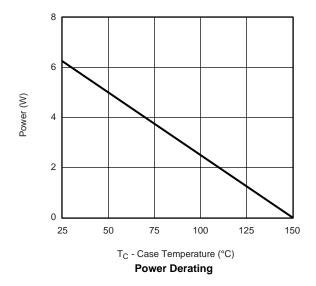
 $\label{eq:VDS} V_{DS} \mbox{ - Drain-to-Source Voltage (V)} $$^*V_{GS} > $$ minimum $V_{GS}$ at which $R_{DS(on)}$ is specified $$$ 

100

Single Pulse Power, Junction-to-Case

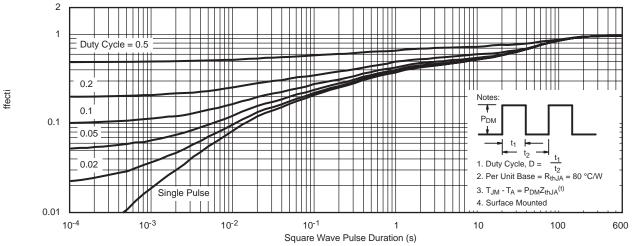




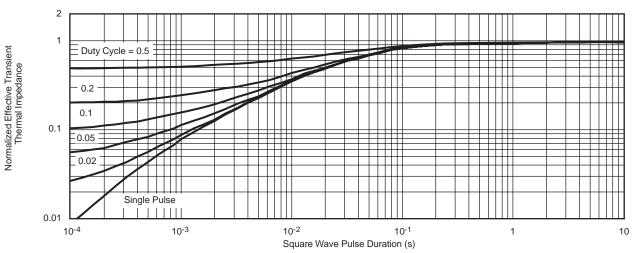


<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





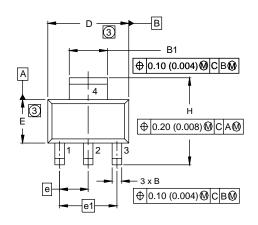
Normalized Thermal Transient Impedance, Junction-to-Ambient

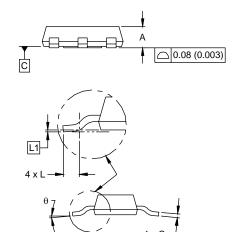


Normalized Thermal Transient Impedance, Junction-to-Foot



### **SOT-223 (HIGH VOLTAGE)**





DIM.	MILLIMETERS		METERS INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	1.55	1.80	0.061	0.071
В	0.65	0.85	0.026	0.033
B1	2.95	3.15	0.116	0.124
С	0.25	0.35	0.010	0.014
D	6.30	6.70	0.248	0.264
E	3.30	3.70	0.130	0.146
е	2.30 BSC		0.090	5 BSC
e1	4.60 BSC		0.181	BSC
Н	6.71	7.29	0.264	0.287
L	0.91	-	0.036	=
L1	0.061 BSC		0.0024	4 BSC
θ	-	10'	-	10'

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.



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DMN2080UCB4-7 DMN61D9UWQ-13 US6M2GTR DMN31D5UDJ-7 DMP22D4UFO-7B DMN1006UCA6-7 DMN16M9UCA6-7
STF5N65M6 IRF40H233XTMA1 STU5N65M6 DMN6022SSD-13 DMN13M9UCA6-7 DMTH10H4M6SPS-13 DMN2990UFB-7B
IPB80P04P405ATMA2 2N7002W-G MCAC30N06Y-TP MCQ7328-TP BXP7N65D BXP4N65F AOL1454G WMJ80N60C4 BXP2N20L
BXP2N65D BXT1150N10J BXT1700P06M TSM60NB380CP ROG RQ7L055BGTCR DMNH15H110SK3-13 SLF10N65ABV2
BSO203SP BSO211P IPA60R230P6 IPA60R460CE